

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: L0306-02 DATE: 7/3/03 Product Affected: Please see attachment for the product list		t □ Product Mark □ Back Mark ■ Date Code	■ Date Code Prefix (Stepping) change. Please see					
Date Effective:	October 2, 2003	□ Other	attachment for details.					
Contact:	Bimla Paul							
Title:	Quality Assurance Manager	Attachment::	Yes No					
Phone #:	(408)-654-6419	a						
Fax #:	(408)-492-8362	Samples: Av	vailable upon request.					
E-mail:	bimla.paul@idt.com							
 DESCRIPTION Die Technolog Wafer Fabrica Assembly Pro Equipment Material Testing Manufacturing Data Sheet Other 	tion Process Selected Logic process facility in Hillsbo Please see attach	oro, Oregon (Fab 4). 7	red to IDT's wafer fab There is no change in die technology. st and qualification data.					
RELIABILITY/QUALIFICATION SUMMARY: Please see attachment for qualification data.								
CUSTOMER ACKNOWLEDGMENT OF RECEIPT: IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable. IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.								
Customer:		□ Approval f	or shipments prior to effective date.	•				
Name/Date:		E-Mail Address:						
Title:		Phone# /Fax# :						
CUSTOMER C	OMMENTS:							
IDT ACKNOW	LEDGMENT OF RECEIPT:							
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RECD. BY: IDT FRA-1509-0	1 REV. 00 09/18/01 Pa	DATE: age 1 of 1	Refer To QCA-17	/95				



Integrated Device Technology, Inc. 2975 Stender Way, Santa Clara, CA - 95054

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- PCN Type: Fab Site Change
- Data Sheet Change: None

Detail of Change:

Transfer existing qualified products to Hillsboro, Oregon Wafer Fab Facility (Fab 4). There is no change in die technology.

The following devices are affected by this change. All packages and speed grades are affected.

Part Number	Old Stepping	New Stepping (Fab 4)
IDTQS32XVH2245	Z	Z4
IDTQS34XVH2245	Ζ	Z4
IDTQS34XVH245	Ζ	Z4
IDTQS32X383	Ζ	Z4
IDTQS32XVH384	Ζ	Z4
IDTQS3306	Y, QA	Z

Conversion Schedule:

Die Revision	Sample Availability:	Production Shipment:
Z4 Stepping	Available	September 29, 2003
Z Stepping	Available	September 29, 2003



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Qualification Plans:

Following reliability tests were performed per process and device families. The qualification results are as follow:

	Required Sample/ # Fails	Process Family Data	Z4 Device Family	Z Device Family
Operating Life Test: Dynamic 1000 hrs @ 125°C or equivalent	116/0	116/0	116/0	116/0
Temperature Cycling 500 Cycles -65°C to +150°C	45/0	45/0	N/A	N/A
Highly Accelerated Stress Test 100 hours	45/0	45/0	N/A	N/A
ESD Human Body Model	3/0	N/A	2500V (3/0)	3500V (3/0)
ESD Charged Device Model	3/0	N/A	1000V (3/0)	1000V (3/0)
Latch up: (Tested to 1.5X Vcc)	10/0	N/A	10/0	10/0

Characterization Data:

Characterization data is available upon request.